

# SKM800GA125D



SEMITRANS® 4

## SKM800GA125D

### Features

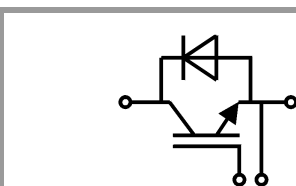
- Homogeneous Si
- NPT-IGBT
- $V_{CE(sat)}$  with positive temperature coefficient
- High short circuit capability, self limiting to  $6 \times I_C$

### Typical Applications\*

- Resonant inverters up to 100 kHz
- Inductive heating
- Electronic welders at  $f_{sw} > 20$  kHz

### Remarks

- $I_{DC} \leq 500$  A limited by terminals
- Take care of over-voltage caused by stray inductances



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Absolute Maximum Ratings			
Symbol	Conditions	Values	Unit
<b>IGBT</b>			
$V_{CES}$	$T_j = 25\text{ °C}$	1200	V
$I_C$	$T_j = 150\text{ °C}$	$T_c = 25\text{ °C}$	760
		$T_c = 80\text{ °C}$	530
$I_{Cnom}$		600	A
$I_{CRM}$	$I_{CRM} = 2 \times I_{Cnom}$	1200	A
$V_{GES}$		-20 ... 20	V
$t_{psc}$	$V_{CC} = 600\text{ V}$	$T_j = 125\text{ °C}$	10
	$V_{GE} \leq 15\text{ V}$		
	$V_{CES} \leq 1200\text{ V}$		
$T_j$		-40 ... 150	°C
<b>Inverse diode</b>			
$I_F$	$T_j = 150\text{ °C}$	$T_c = 25\text{ °C}$	720
		$T_c = 80\text{ °C}$	500
$I_{Fnom}$		600	A
$I_{FRM}$	$I_{FRM} = 2 \times I_{Fnom}$	1200	A
$I_{FSM}$	$t_p = 10\text{ ms, sin } 180^\circ, T_j = 25\text{ °C}$	5760	A
$T_j$		-40 ... 150	°C
<b>Module</b>			
$I_{t(RMS)}$	$T_{terminal} = 80\text{ °C}$	500	A
$T_{stg}$		-40 ... 125	°C
$V_{isol}$	AC sinus 50 Hz, $t = 1\text{ min}$	4000	V

Characteristics					
Symbol	Conditions	min.	typ.	max.	Unit
<b>IGBT</b>					
$V_{CE(sat)}$	$I_C = 600\text{ A}$ $V_{GE} = 15\text{ V}$ chipelevel	$T_j = 25\text{ °C}$	3.20	3.70	V
		$T_j = 125\text{ °C}$	4.00	4.80	V
$V_{CE0}$	chipelevel	$T_j = 25\text{ °C}$	1.5	1.75	V
		$T_j = 125\text{ °C}$	1.7	1.95	V
$r_{CE}$	$V_{GE} = 15\text{ V}$ chipelevel	$T_j = 25\text{ °C}$	2.83	3.25	mΩ
		$T_j = 125\text{ °C}$	3.83	4.75	mΩ
$V_{GE(th)}$	$V_{GE} = V_{CE}, I_C = 24\text{ mA}$	4.5	5.5	6.5	V
$I_{CES}$	$V_{GE} = 0\text{ V}$ $V_{CE} = 1200\text{ V}$	$T_j = 25\text{ °C}$		0.6	mA
					mA
$C_{ies}$	$V_{CE} = 25\text{ V}$	$f = 1\text{ MHz}$	37.2		nF
$C_{oes}$	$V_{GE} = 0\text{ V}$	$f = 1\text{ MHz}$	5.6		nF
$C_{res}$		$f = 1\text{ MHz}$	2.80		nF
$Q_G$	$V_{GE} = -8\text{ V...} + 20\text{ V}$		4200		nC
$R_{Gint}$	$T_j = 25\text{ °C}$		0.5		Ω
$t_{d(on)}$	$V_{CC} = 600\text{ V}$ $I_C = 600\text{ A}$	$T_j = 125\text{ °C}$	480		ns
$t_r$	$V_{GE} = \pm 15\text{ V}$	$T_j = 125\text{ °C}$	116		ns
$E_{on}$	$R_{Gon} = 0.5\text{ Ω}$	$T_j = 125\text{ °C}$	88		mJ
$t_{d(off)}$	$R_{Goff} = 0.5\text{ Ω}$	$T_j = 125\text{ °C}$	666		ns
$t_f$		$T_j = 125\text{ °C}$	58		ns
$E_{off}$		$T_j = 125\text{ °C}$	48		mJ
$R_{th(j-c)}$	per IGBT			0.03	K/W



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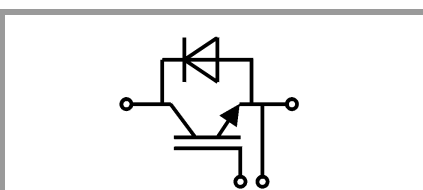
### Typical Applications\*

- Resonant inverters up to 100 kHz
- Inductive heating
- Electronic welders at  $f_{sw} > 20$  kHz

### Remarks

- $I_{DC} \leq 500$  A limited by terminals
- Take care of over-voltage caused by stray inductances

Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
<b>Inverse diode</b>						
$V_F = V_{EC}$	$I_F = 600$ A $V_{GE} = 0$ V chipllevel	$T_j = 25$ °C		2.3	2.58	V
		$T_j = 125$ °C		1.87	2.38	V
$V_{F0}$	chipllevel	$T_j = 25$ °C		1.1	1.45	V
		$T_j = 125$ °C		0.85	1.2	V
$r_F$	chipllevel	$T_j = 25$ °C		1.6	1.9	mΩ
		$T_j = 125$ °C		1.7	2	mΩ
$I_{RRM}$	$I_F = 600$ A	$T_j = 125$ °C		370		A
$Q_{rr}$	$V_{GE} = \pm 15$ V $V_{CC} = 600$ V	$T_j = 125$ °C		83		μC
$E_{rr}$		$T_j = 125$ °C		28		mJ
$R_{th(j-c)}$	per diode				0.07	K/W
<b>Module</b>						
$L_{CE}$				15	20	nH
$R_{CC'+EE'}$	terminal-chip	$T_C = 25$ °C		0.18		mΩ
		$T_C = 125$ °C		0.22		mΩ
$R_{th(c-s)}$	per module			0.02	0.038	K/W
$M_s$	to heat sink M6			3	5	Nm
$M_t$	to terminals	M6		2.5	5	Nm
		M4		1.1	2	Nm
$w$					330	g



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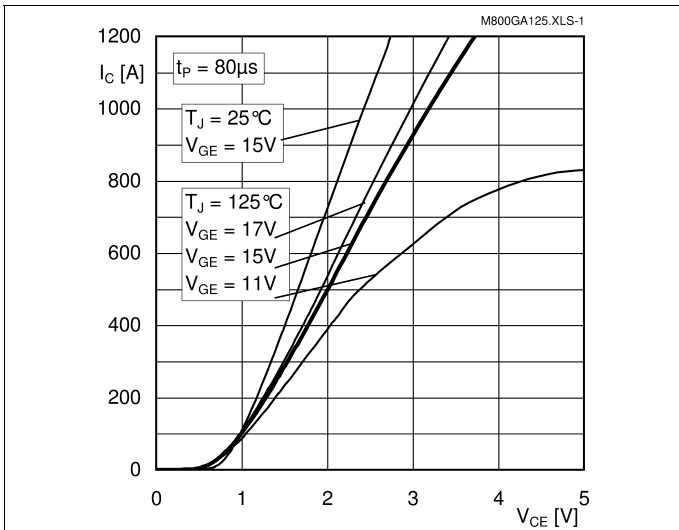


Fig. 1: Typ. output characteristic, inclusive  $R_{CC+EE}$

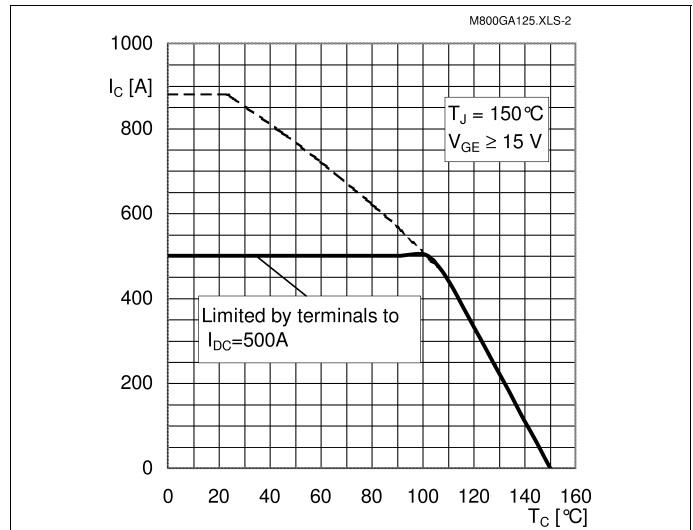


Fig. 2: Rated current vs. temperature  $I_C = f(T_C)$

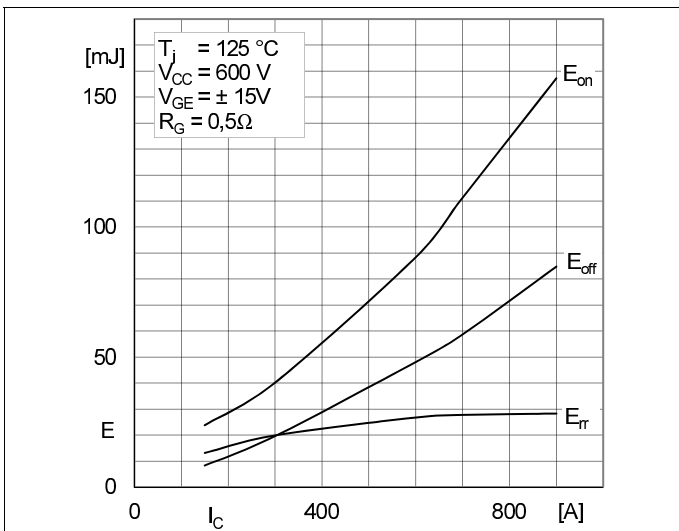


Fig. 3: Typ. turn-on /-off energy =  $f(I_C)$

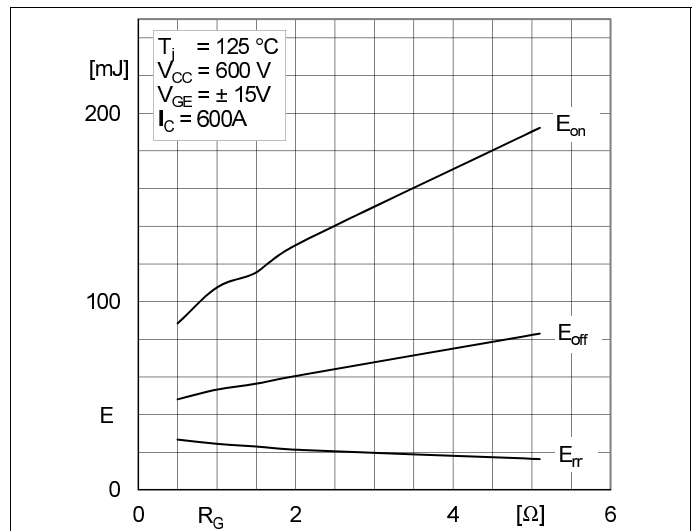


Fig. 4: Typ. turn-on /-off energy =  $f(R_G)$

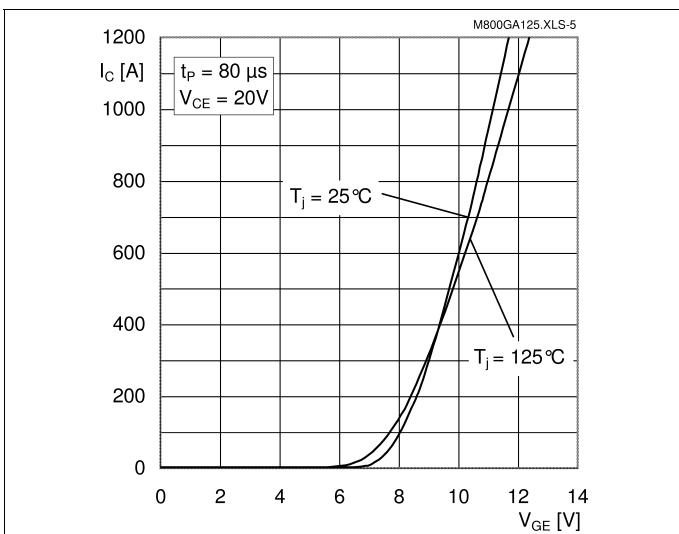


Fig. 5: Typ. transfer characteristic

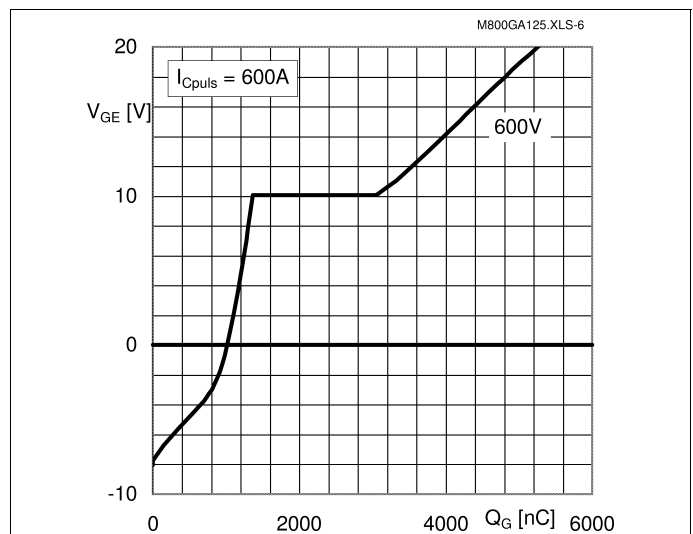


Fig. 6: Typ. gate charge characteristic

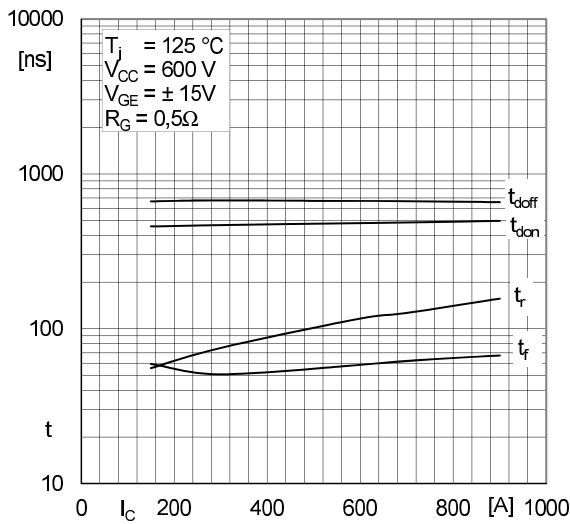


Fig. 7: Typ. switching times vs.  $I_C$

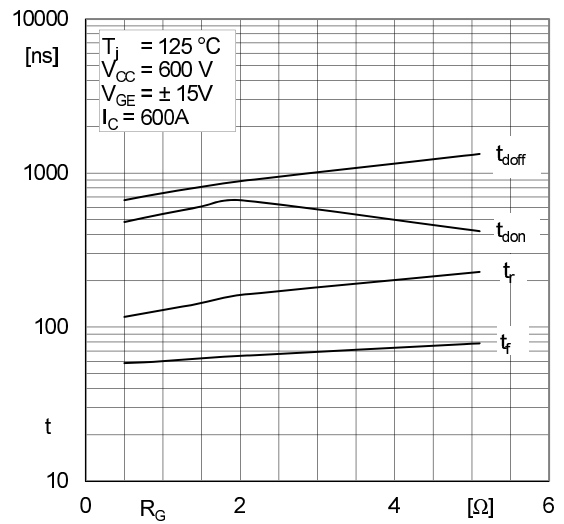


Fig. 8: Typ. switching times vs. gate resistor  $R_G$

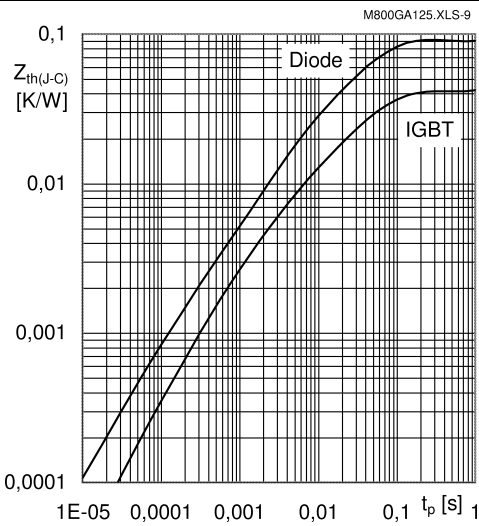


Fig. 9: Transient thermal impedance

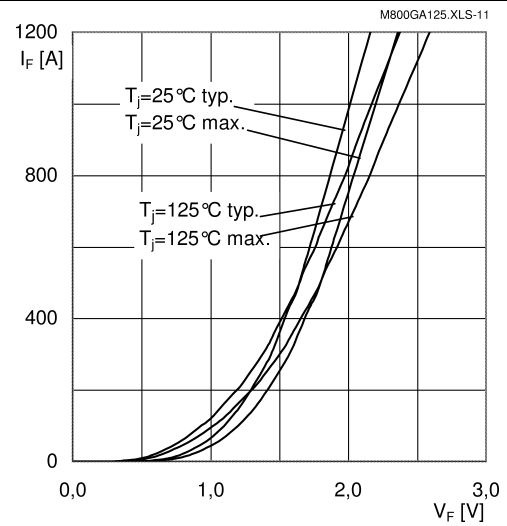


Fig. 10: Typ. CAL diode forward charact., incl.  $R_{CC+EE'}$

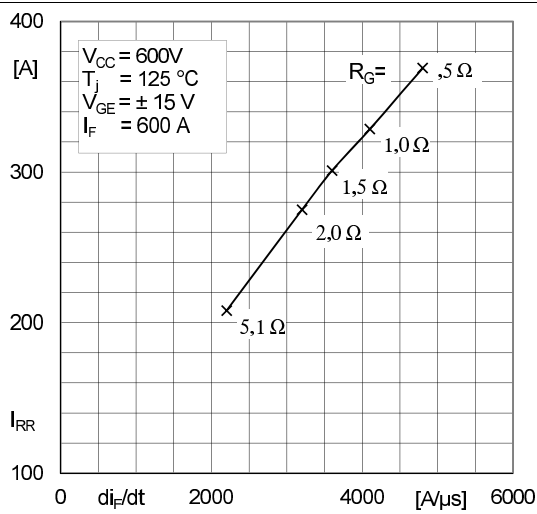


Fig. 11: CAL diode peak reverse recovery current

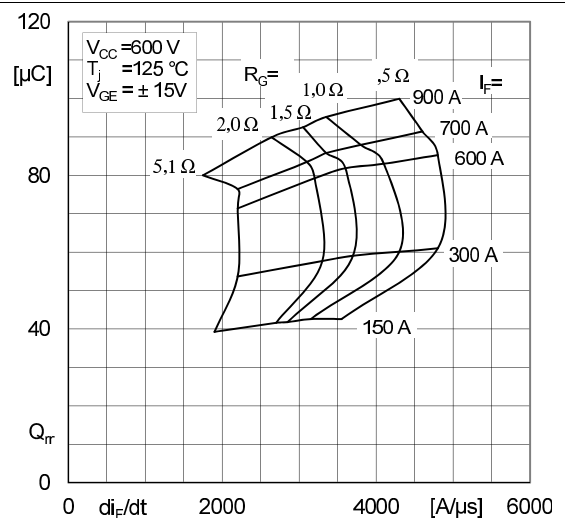
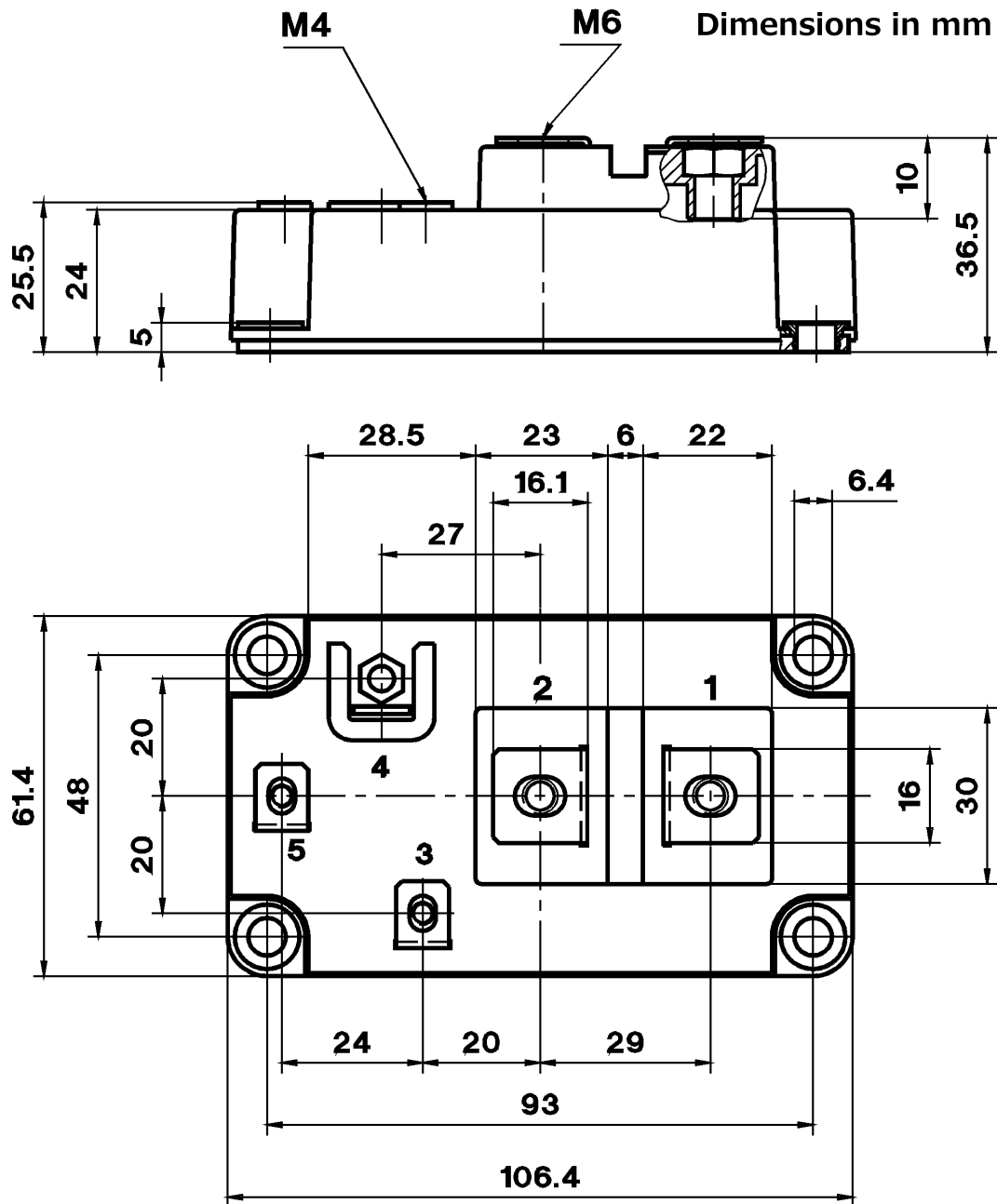
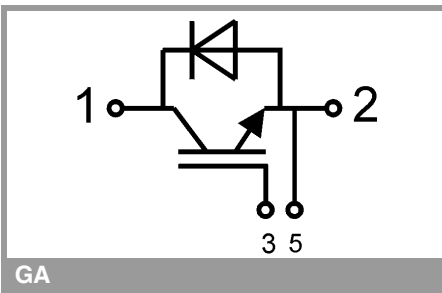


Fig. 12: Typ. CAL diode peak reverse recovery charge



General tolerance  $\pm 0.5$  mm

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This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, Chapter IX

\* The specifications of our components may not be considered as an assurance of component characteristics. Components have to be tested for the respective application. Adjustments may be necessary. The use of SEMIKRON products in life support appliances and systems is subject to prior specification and written approval by SEMIKRON. We therefore strongly recommend prior consultation of our staff.